

Notice of References Cited

Application/Control No.

10/825,363

Applicant(s)/Patent Under
Reexamination
LEE ET AL.

Examiner

ALLISON WALTHALL

Art Unit

2629

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0026283 A1	10-2001	Yoshida et al.	345/600
*	B	US-7,158,156 B2	01-2007	Endou, Shinji	345/77
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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